

# **RMLV0408E Series**

4Mb Advanced LPSRAM (512k word × 8bit)

R10DS0217EJ0001 Rev.0.01 2013.09.10

# Description

The RMLV0408E Series is a family of 4-Mbit static RAMs organized 524,288-word × 8-bit, fabricated by Renesas's high-performance Advanced LPSRAM technologies. The RMLV0408E Series has realized higher density, higher performance and low power consumption. The RMLV0408E Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is offered in 32-pin SOP, 32-pin TSOP II or 32-pin STSOP.

# Features

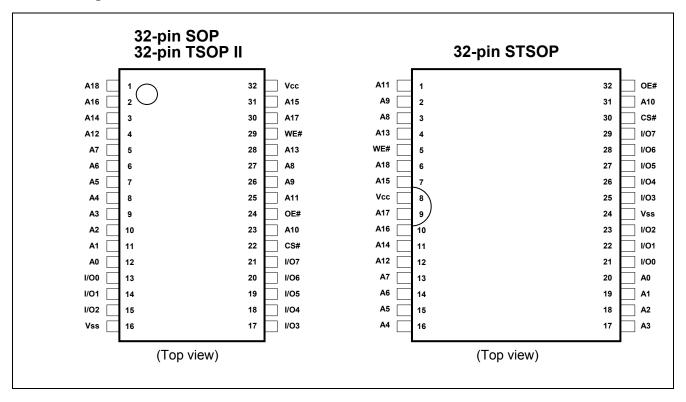
- Single 3V supply: 2.7V to 3.6V
- Access time: 45/55ns (max.)
- Current consumption: — Standby: 0.4µA (typ.)
- Equal access and cycle times
- Common data input and output — Three state output
- Directly TTL compatible — All inputs and outputs
- Battery backup operation

# **Part Name Information**

Part Name	Access time	Temperature Range	Package		
RMLV0408EGSP-4S2	45 ns		E2E mil 22 nin alastia SOD		
RMLV0408EGSP-5S2	55 ns		525-mil 32-pin plastic SOP		
RMLV0408EGSB-4S2	45 ns	40 105%			
RMLV0408EGSB-5S2	55 ns	-40 ~ +85°C	400-mil 32-pin plastic TSOP II		
RMLV0408EGSA-4S2	45 ns				
RMLV0408EGSA-5S2	55 ns		8mm x 13.4mm STSOP		



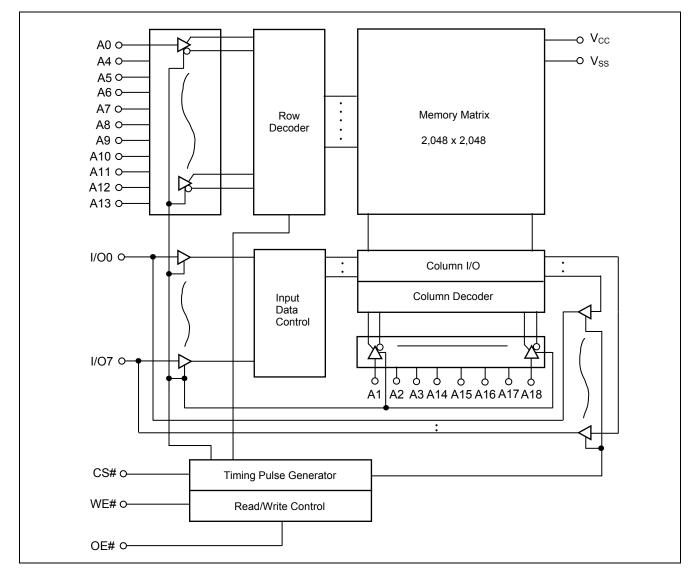
# **Pin Arrangement**



# **Pin Description**

Pin name	Function	
Vcc	Power supply	
V <sub>SS</sub>	Ground	
A0 to A18	Address input	
I/O0 to I/O7	Data input/output	
CS#	Chip select	
WE#	Write enable	
OE#	Output enable	

# **Block Diagram**



# **Operation Table**

CS#	WE#	OE#	I/O0 to I/O7	Operation
Н	Х	Х	High-Z	Standby
L	Н	L	Dout	Read
L	L	Х	Din	Write
L	Н	Н	High-Z	Output disable

Note 1. H:  $V_{IH}$  L:  $V_{IL}$  X:  $V_{IH}$  or  $V_{IL}$ 

# **Absolute Maximum Ratings**

Parameter	Symbol	Value	unit
Power supply voltage relative to V <sub>SS</sub>	V <sub>cc</sub>	-0.5 to +4.6	V
Terminal voltage on any pin relative to $V_{SS}$	V <sub>T</sub>	-0.5 <sup>*2</sup> to V <sub>CC</sub> +0.3 <sup>*3</sup>	V
Power dissipation	PT	0.7	W
Operation temperature	Topr	-40 to +85	°C
Storage temperature range	Tstg	-65 to +150	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Note 2. -3.0V for pulse  $\leq$  30ns (full width at half maximum)

3. Maximum voltage is +4.6V.

### **DC Operating Conditions**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Note
Supply voltage	V <sub>CC</sub>	2.7	3.0	3.6	V	
	V <sub>SS</sub>	0	0	0	V	
Input high voltage	V <sub>IH</sub>	2.2	I	V <sub>CC</sub> +0.3	V	
Input low voltage	V <sub>IL</sub>	-0.3	-	0.6	V	4
Ambient temperature range	Та	-40	_	+85	°C	

Note 4. -3.0V for pulse  $\leq$  30ns (full width at half maximum)

## **DC Characteristics**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions			
Input leakage current	I <sub>LI</sub>	-	-	1	μA	Vin = $V_{SS}$ to $V_{CC}$			
Output leakage current	I <sub>LO</sub>	_	_	1	μA	CS# =V <sub>IH</sub> VI/O = V <sub>S</sub>	or OE# =V <sub>IH</sub> or WE#= V <sub>IL</sub> , s to V <sub>CC</sub>		
Operating current	Icc	_	-	10	mA	CS# =V <sub>IL</sub> Others =	, V <sub>IH</sub> /V <sub>IL</sub> , II/O = 0mA		
Average operating current	I <sub>CC1</sub>	_	_	20	mA	-	e, duty =100%, II/O = 0mA , Others = V <sub>IH</sub> /V <sub>IL</sub>		
	I <sub>CC2</sub>	-	_	2.5	mA	Cycle =1µs, duty =100%, II/O = 0mA CS# ≤ 0.2V, V <sub>IH</sub> ≥ Vcc-0.2V, V <sub>IL</sub> ≤ 0.2V			
Standby current	I <sub>SB</sub>	_	0.1 <sup>*5</sup>	0.3	mA		CS# =V <sub>IH</sub> , Others = V <sub>SS</sub> to V <sub>CC</sub>		
Standby current		_	0.4 <sup>*5</sup>	2	μA	~+25°C			
		_	_	3	μΑ	~+40°C	Vin = $V_{SS}$ to $V_{CC}$ ,		
	I <sub>SB1</sub>	_	_	5	μΑ	~+70°C	CS# ≥ V <sub>CC</sub> -0.2V		
		_	_	7	μA	~+85°C			
Output high voltage	V <sub>OH</sub>	2.4	_	_	V	I <sub>OH</sub> = -1mA			
	V <sub>OH2</sub>	V <sub>CC</sub> -0.2	_	_	V	I <sub>OH</sub> = -0.1mA			
Output low voltage	V <sub>OL</sub>	—	_	0.4	V	I <sub>OL</sub> = 2.1mA			
	V <sub>OL2</sub>	—	_	0.2	V	I <sub>OL</sub> = 0.1r	nA		

Note 5. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=25°C), and not 100% tested.

### Capacitance

 $(Vcc = 2.7V \sim 3.6V, f = 1MHz, Ta = -40 \sim +85^{\circ}C^{*2})$ 

		```		-	- ,	,	,
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Input capacitance	C in	-	—	8	pF	Vin =0V	6
Input / output capacitance	C <sub>I/O</sub>	-	—	10	pF	V <sub>I/O</sub> =0V	6

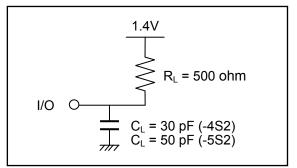
Note 6. This parameter is sampled and not 100% tested.



# **AC Characteristics**

Test Conditions (Vcc =  $2.7V \sim 3.6V$ , Ta =  $-40 \sim +85^{\circ}C$ )

- Input pulse levels:  $V_{IL} = 0.4V$ ,  $V_{IH} = 2.4V$
- Input rise and fall time: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



#### **Read Cycle**

Parameter	Symbol	RMLV040	8EG**-4S2	RMLV0408	EG**-5S2	Unit	Note
Faranielei	Symbol	Min.	Max.	Min.	Max.	Unit	NOLE
Read cycle time	t <sub>RC</sub>	45	—	55	—	ns	
Address access time	t <sub>AA</sub>	—	45	—	55	ns	
Chip select access time	t <sub>ACS</sub>	-	45	-	55	ns	
Output enable to output valid	t <sub>OE</sub>	-	22	-	30	ns	
Output hold from address change	t <sub>он</sub>	10	-	10	_	ns	
Chip select to output in low-Z	t <sub>CLZ</sub>	10	-	10	_	ns	7,8
Output enable to output in low-Z	t <sub>OLZ</sub>	5	-	5	_	ns	7,8
Chip deselect to output in high-Z	t <sub>CHZ</sub>	0	18	0	20	ns	7,8,9
Output disable to output in high-Z	t <sub>OHZ</sub>	0	18	0	20	ns	7,8,9

#### Write Cycle

Parameter	Symbol	RMLV0408EG**-4S2		RMLV0408	EG**-5S2	Unit	Note
Faranielei	Symbol	Min.	Max.	Min.	Max.	Unit	Note
Write cycle time	t <sub>WC</sub>	45	_	55	-	ns	
Address valid to write end	t <sub>AW</sub>	35	_	50	-	ns	
Chip select to write end	t <sub>CW</sub>	35	_	50	I	ns	
Write pulse width	t <sub>WP</sub>	35	—	40	I	ns	10
Address setup time to write start	t <sub>AS</sub>	0	_	0	I	ns	
Write recovery time from write end	t <sub>WR</sub>	0	_	0	I	ns	
Data to write time overlap	t <sub>DW</sub>	25	_	25	I	ns	
Data hold from write end	t <sub>DH</sub>	0	_	0	I	ns	
Output enable from write end	tow	5	—	5	-	ns	7
Output disable to output in high-Z	t <sub>OHZ</sub>	0	18	0	20	ns	7,9
Write to output in high-Z	t <sub>WHZ</sub>	0	18	0	20	ns	7,9

Note 7. This parameter is sampled and not 100% tested.

8. At any given temperature and voltage condition,  $t_{CHZ}$  max is less than  $t_{CLZ}$  min, and  $t_{OHZ}$  max is less than  $t_{OLZ}$  min, for any device.

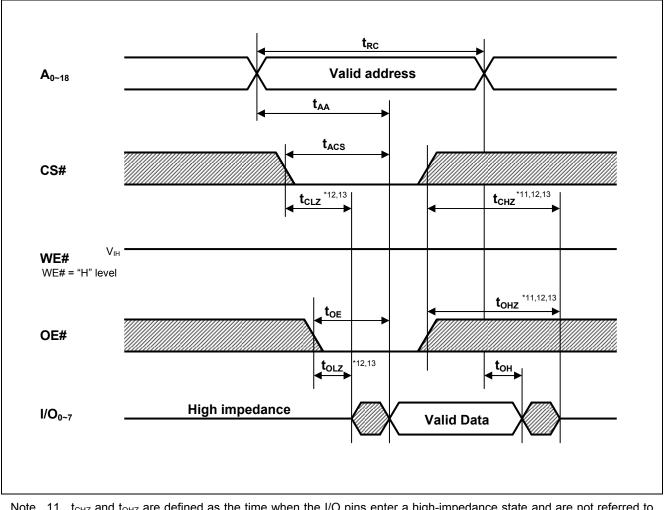
9.  $t_{CHZ}$ ,  $t_{OHZ}$  and  $t_{WHZ}$  are defined as the time when the I/O pins enter a high-impedance state and are not referred to the I/O levels.

t<sub>WP</sub> is the interval between write start and write end.
 A write starts when both of CS# and WE# become active
 A write is performed during the overlap of a low CS#, a low WE#
 A write ends when any of CS#, WE# becomes inactive.



# **Timing Waveforms**

#### **Read Cycle**

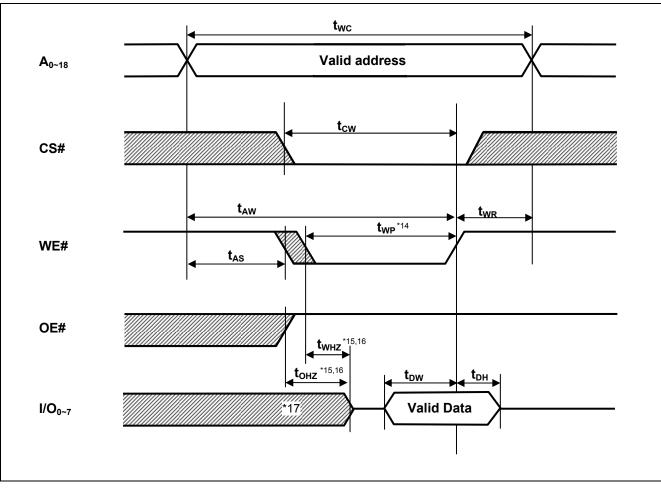


Note 11.  $t_{CHZ}$  and  $t_{OHZ}$  are defined as the time when the I/O pins enter a high-impedance state and are not referred to the I/O levels.

- 12. This parameter is sampled and not 100% tested.
- 13. At any given temperature and voltage condition,  $t_{CHZ}$  max is less than  $t_{CLZ}$  min, and  $t_{OHZ}$  max is less than  $t_{OLZ}$  min, for any device.



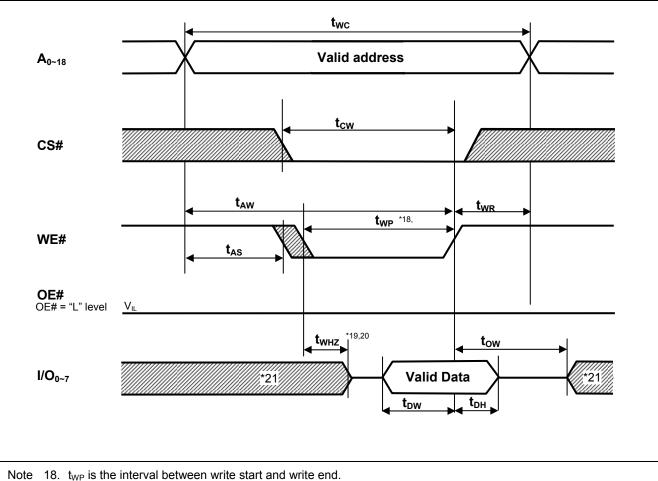
#### Write Cycle (1) (WE# CLOCK, OE#="H" while writing)



Note 14. t<sub>WP</sub> is the interval between write start and write end. A write starts when both of CS# and WE# become active. A write is performed during the overlap of a low CS# and a low WE#. A write ends when any of CS# or WE# becomes inactive.

- 15.  $t_{OHZ}$  and  $t_{WHZ}$  are defined as the time when the I/O pins enter a high-impedance state and are not referred to the I/O levels.
- 16. This parameter is sampled and not 100% tested.
- 17. During this period, I/O pins are in the output state so input signals must not be applied to the I/O pins.

#### Write Cycle (2) (WE# CLOCK, OE# Low Fixed)



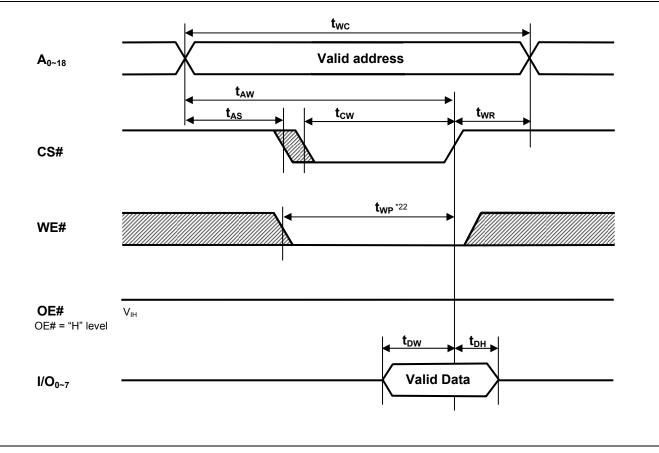
A write starts when both of CS# and WE# become active.

A write is performed during the overlap of a low CS# and a low WE#.

A write ends when any of CS# or WE# becomes inactive.

- 19.  $t_{WHZ}$  is defined as the time when the I/O pins enter a high-impedance state and are not referred to the I/O levels.
- 20. This parameter is sampled and not 100% tested.
- 21. During this period, I/O pins are in the output state so input signals must not be applied to the I/O pins.

# Write Cycle (3) (CS# CLOCK)



Note 22.  $t_{WP}$  is the interval between write start and write end.

A write starts when both of CS# and WE# become active.

A write is performed during the overlap of a low CS# and a low WE#.

A write ends when any of CS# or WE# becomes inactive.

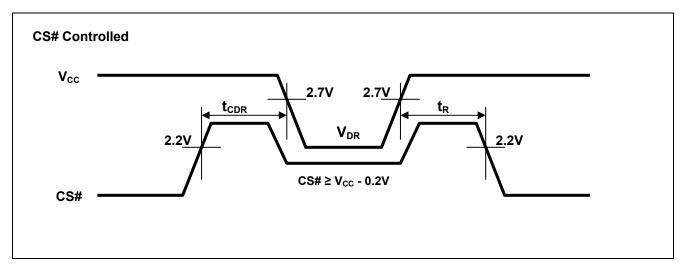
#### Low V<sub>CC</sub> Data Retention Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions <sup>*24</sup>		
$V_{CC}$ for data retention	$V_{\text{DR}}$	1.5	_	Ι	V	Vin ≥ 0V, CS# ≥ V <sub>CC</sub> -0.2V		
	ICCDR	_	0.4 <sup>*23</sup>	2	μA	~+25°C		
Data ratantian surrant		Ι	_	3	μA	~+40°C	V <sub>CC</sub> =3.0V, Vin ≥ 0V,	
Data retention current		-	_	5	μA	~+70°C	CS# ≥ Vcc-0.2V	
		_	_	7	μA	~+85°C		
Chip deselect time to data retention	t <sub>CDR</sub>	0	_	I	ns	See retention waveform.		
Operation recovery time	t <sub>R</sub>	5	_	_	ms			

Note 23. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=25°C), and not 100% tested.
24. CS# controls address buffer, WE# buffer, OE# buffer, and I/O buffer. If CS# controls data retention mode, Vin

levels (address, WE#, OE#, I/O) can be in the high-impedance state.

#### Low Vcc Data Retention Timing Waveforms (CS# controlled)



Revision History	RMLV0408E Series Data Sheet
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			Description					
Rev.	Date	Page	Summary					
0.01	2013.09.10	—	Preliminary First Edition issued					

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